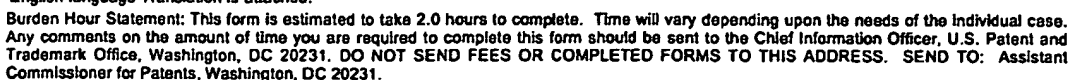




FORM PTO-1449		Docket Number (Optional) 294G 1787-4		Application Number 10/028,231		
INFORMATION DISCLOSURE CITATION IN AN APPLICATION		Applicant Colbert et al.				
(Use several sheets if necessary)		Filing Date 12/21/2001		Group Art Unit 2881-		
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION (YES/NO)
or	JP H06-331309	12/2/1994	Japan			
or	JP H06-252056	9/9/1994	Japan			
or	JP H07-122198	5/12/1995	Japan			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
or	"Imaging steep, high structures by scanning force microscopy with electron beam deposited tips" by David J. Keller, et al., pages 333-339 in the <i>Surface Science</i> magazine published by Elsevier Science Publishers B.V. in 1992 in Holland					
or	"New Scanning tunneling microscopy tip for measuring surface topography" by Y. Akama, et al., pages 429-433 in <i>Vac. Sci. Technol. A 8</i> published by American Vacuum Society in 1990					
or	"Atomic force microscopy using ZnO whisker tip" by H. Kado, et al., pages 3330-3332 in <i>Rev. Sci. Instrum</i> 63 published by American Institute of Physics in 1992					
or	"Helical microtubules of graphitic carbon" by Sumio Iijima, pages 56-58 in the <i>Nature</i> magazine Vo. 354 published in 1991					
or	"Single-shell carbon nanotubes of 1-nm diameter" by Sumio Iijima et al., pages 603-605 in the <i>Nature</i> magazine Vo. 363 published in 1993					
or	"Aligned Carbon Nanotube Arrays Formed by Cutting a Polymer Resin-Nanotube Composite" by P.M Ajaya, et al., pages 1212-1214 in the <i>SCIENCE</i> magazine Vo. 265 published in 1994					
or	"Aligned Carbon Nanotube Films: Production and Optical and Electronic Properties" by Walt A. de Heer, et al., pages 845-847 in the <i>SCIENCE</i> magazine Vo. 268 published in 1995					
EXAMINER	DATE CONSIDERED					
or	6-24-05					
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number	10/028,231
				Filing Date	December 21, 2001
				First Named Inventor	Colbert, et al.
				Group Art Unit	2881
				Examiner Name	Unknown
				Attorney Docket Number	11321-P011C1D1
Sheet	2	of	2		

[illegible]

Examiner Signature	<i>G. L. ...</i>	Date Considered	6-29-05
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